

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10/037,329	ISHII, MIRUKA	
	Examiner James D. Ewart	Art Unit 2617	Page 1 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,553,178	04-2003	Abecassis, Max	386/83
*	B	US-7,149,471	12-2006	Arisawa et al.	455/3.04
*	C	US-5,652,784	07-1997	Blen et al.	379/67.1
*	D	US-6,484,148	11-2002	Boyd, John E.	705/14
*	E	US-6,603,844	08-2003	Chavez et al.	379/114.13
*	F	US-6,304,651	10-2001	Cramer et al.	379/221.01
*	G	US-6,385,308	05-2002	Cohen et al.	379/88.23
*	H	US-5,724,521	03-1998	Dedrick, Rick	705/26
*	I	US-2004/0105534	06-2004	Dezonno, Anthony	379/114.13
*	J	US-7,072,867	07-2006	Dutta, Rabindranath	705/53
*	K	US-5,353,335	10-1994	D'Urso et al.	379/114.2
*	L	US-6,442,244	08-2002	Fellingham et al.	379/76
*	M	US-2001/0032193	10-2001	Ferber, John B.	705/79

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination ISHII, MIRUKA	
		Examiner James D. Ewart	Art Unit 2617	Page 2 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0087656	07-2002	Gargiulo et al.	709/217
*	B	US-2001/0048737	12-2001	GOLDBERG et al.	379/114.13
*	C	US-2001/0056374	12-2001	Joao, Raymond Anthony	705/14
*	D	US-6,009,150	12-1999	Kamel, Alexandre P.	379/88.22
*	E	US-5,937,037	08-1999	Kamel et al.	379/88.19
*	F	US-6,442,529	08-2002	Krishan et al.	705/14
*	G	US-5,452,354	09-1995	Kyronlahti et al.	379/373.02
*	H	US-6,418,330	07-2002	Lee, Hyeon-Woo	455/567
*	I	US-6,366,791	04-2002	Lin et al.	455/567
*	J	US-4,850,007	07-1989	Marino et al.	379/114.13
*	K	US-2001/0034651	10-2001	Marks et al.	705/14
*	L	US-7,039,599	05-2006	Merriman et al.	705/14
*	M	US-5,987,424	11-1999	Nakamura, Toshio	705/14

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/037,329 ISHII, MIRUKA	
		Examiner James D. Ewart	Art Unit 2617	Page 3 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,567,854	05-2003	Olshansky et al.	709/229
*	B	US-6,493,437	12-2002	Olshansky, Robert	379/114.13
*	C	US-6,618,474	09-2003	Reese, Morris	379/142.17
*	D	US-2003/0086558	05-2003	Seelig et al.	379/373.01
*	E	US-4,811,382	03-1989	Sleevi, Neil F.	379/67.1
*	F	US-2001/0051517	12-2001	Strietzel, Jonathan	455/414
*	G	US-6,606,376	08-2003	Trell, Anders Edvard	379/102.06
*	H	US-6,018,654	01-2000	Valentine et al.	455/414.4
*	I	US-5,931,901	08-1999	Wolfe et al.	709/206
*	J	US-6,018,720	01-2000	Fujimoto, Jun	705/26
*	K	US-6,816,878	11-2004	Zimmers et al.	709/200
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.